

Notice of References Cited	Application/Control No. 10/719,010	Applicant(s)/Patent Under Reexamination XI, JUNNAN	
	Examiner Edgardo San Martin	Art Unit 2837	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,232,752	05-2001	Bissell, Stephen R.	323/222
	B	US-2004/0070862 a1	04-2004	Ranmuthu, Indumini	360/068
	C	US-2004/0047167 a1	03-2004	Prasad et al.	363/125
	D	US-2003/0205974 a1	11-2003	Kuehner et al.	318/254
	E	US-6,611,127	08-2003	Arimitsu et al.	318/254
	F	US-6,331,365	12-2001	King, Robert Dean	320/103
	G	US-6,060,859	05-2000	Jonokuchi, Hideki	318/801
	H	US-5,874,826	02-1999	Chen et al.	323/222
	I	US-5,737,144	04-1998	Ataee et al.	318/254
	J	US-5,519,306	05-1996	Itoh et al.	323/222
	K	US-5,442,260	08-1995	Saito et al.	315/241P
	L	US-4,733,159	03-1988	Edwards et al.	323/282
	M	US-4,456,856	06-1984	Klinger, Roland W.	315/408

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003244966 A	08-2003	Japan	OMICHI et al.	H02M 07/48
	O	JP 05083987 A	04-1993	Japan	KAWAKITA, KEISUKE	H02P 07/29
	P	GB 2273212 A	06-1994	United Kingdom	BOLTON et al.	H02P 07/00
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.